

(March 4, 2002)

Sheet 1 of 1

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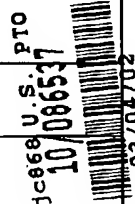
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Herbert Thanner et al.FILING DATE
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FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

<i>1/2m</i>	A.W. Warner, "Design and Performance of Ultraprecise 2.5-mc Quartz Crystal Units," Bell Sys. Techn. J., Sept. 1960, pp. 1193-1217.
<i>1/2m</i>	Ch. Longet et al., "An Electrodeless BT Cut, 5 th Overtone Quartz Crystal Resonator at 50 MHZ," EFTF, 1995, pp. 141-145.
<i>1/2m</i>	R. C. Smythe et al., "Langasite, Langanite, and Langatate Resonators: Recent Results," Joint Meeting EFTF-IEEE IFCS, 1999, pp. 816-820.
<i>1/2m</i>	<u>IEEE Standard on Piezoelectricity</u> , The Institute of Electrical and Electronics Engineers, New York, N.Y. (Jan. 29, 1988).
<i>1/2m</i>	<u>International Tables for X-Ray Crystallography</u> , The Kynoch Press, Birmingham, England (1969), pg. 255.
<i>1/2m</i>	B. V. Mill et al., "Synthesis, Growth and Some Properties of Single Crystals with the Ca ₃ Ga ₂ Ge ₄ O ₁₄ Structure," Joint Meeting EFTF-IEEE IFCS, 1999, pp. 829-834.

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FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES NO

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<i>KRM</i>	C. Reiter et al., "Elastic Constants and Temperature-Compensated Orientations of GaPO₄," 15th European Frequency and Time Forum Neuchatel, XP008009573, 6 March 2001, pp. 50-54.
<i>KRM</i>	E. Philippot et al., "A Quartz-like Material...Characterization" in J. Crystal Growth, 130, No. 1/2, May 1993, pp. 195-208.
<i>KRM</i>	A. Zarka et al., "Studies of GaPO₄ Crystals and Resonators," 1996 IEEE International Frequency Control Symposium, 1996, pp. 66-71.

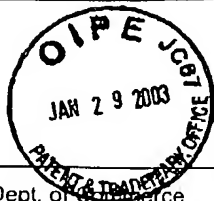
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KRM *June 22, 2004*

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<i>Kmw</i>	S.A. Ssakharov et al., "Application of Langasite...Modes," 1992 IEEE Frequency Control Symposium, 1992, pp. 713-723.
<i>Kmw</i>	H. Fritze et al., "High Temperature...Langasite" in Sensors and Actuators B 76, 1 June 2001, pp. 103-107.
<i>Kmw</i>	M. F. Dubovik et al., "Influence...Crystals," 1996 IEEE International Frequency Control Symposium, 1996, pp. 84-89.

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